

TAAB FIB Supplies

FIB Grid Holders

The TAAB FIB grid holders are designed to hold FIB grids and provide easy access to the posts on the FIB grids to attach the milled FIB lift-out lamellae. The FIB grid holders can be used in the FIB/SEM systems but also for safe storage of the FIB grids with attached lamellae. The FIB grid and sample holders are compact holders which hold the FIB grids directly beside a standard SEM pin stub with a sample. The lift-out lamellae only need to be moved over a short distance to attach them to the FIB grids. The FIB grid holders are all precision machined from vacuum grade aluminium:



F336



F337



F338



F339



F340

F336 A basic, practical, compact FIB grid holder with 3.2mm pin for 2 FIB grids. Based on the standard 12.7mm Ø pin stub and useful for storing valuable samples. The 10mm wide vice clamp includes a ledge for easy positioning of the FIB grids F337 F338

F337 A larger FIB grid holder with 3.2mm pin to take up to 4 FIB grids of the same thickness. The 25mm wide vice include a ledge for easy positioning of the FIB grids and two brass thumb screws to operate the vice.

F337/M as above with M4 Hitachi thread

F338 On 3.2mm pin combines two F336 FIB grid holders with two standard 12.7mm pin stubs within a 27 x 27mm footprint. The F336 FIB grid holders and the pin stubs can be rotated independently in the holder for selecting the optimum orientation in the FIB/SEM system. This dual FIB grid and sample holder enables loading the samples and FIB grids close together. The FIB grid and the sample stubs are at the same level when using Si wafer samples.

F338/M As above with M4 thread

F339 Combines the F336 FIB grid holder with two standard 12.7mm pin stubs on 3.2mm pin. The FIB grid holder and the sample stubs can be rotated in the holder for selecting the optimum orientation in the FIB/SEM system. This FIB grid and sample holder enables loading the samples and FIB grids close together. The FIB grid and the sample stubs are at the same level when using Si wafer samples.

F339/M As above with Hitachi M4 thread

F340 Combines the wider FIB grid holder vice with a holder for samples on the 25.4mm Ø pin stubs in a single compact holder. This provides a single loading cycle for FIB grids and samples and short distances from form lift-out to lamellae mounting. Wafer type sample surface is at the same height as the FIB grid posts.

F340/M As above with M4 thread

FIB Pre-Tilt Stub Holders

Pre-tilt stub holders are useful for FIB/SEM systems to get the sample perpendicular with the FIB column to allow for straight FIB milling into the surface of the sample. The pre-tilt angles are complementary to the angles between the FIB column and the electron beam column. When pre-tilt stub holders are used, there is no need to tilt the sample stage. Three types are available:



S686



S687



S688

S686 Fixed 38° angle tilt holder for FEI pin stubs. Used to pre-tilt samples 38° for FEI Dual Beam FIB systems. Size w.o. pin is 12.7mm Ø x 17mm.

S687 Fixed 36° angle tilt holder for Zeiss pin stubs. Used to pre-tilt samples 36° for Zeiss CrossBeam FIB systems. Size w.o. pin is 12.7mm Ø x 17mm.

S688 Fixed 35° angle tilt holder for standard and Tescan pin stubs. Used to pre-tilt samples 35° for Tescan FIB x SEM systems. Size w.o. pin is 12.7 Ø x 17mm.